

Keithley 4200-SCS Analyzer

Overview

The Keithley 4200-Semiconductor Characterization System (SCS Parameter Analyzer) (with probe station) provides electrical characterization of materials, semiconductor devices, and processes.

LMACS Name	Keithley 4200-Semiconductor Characterization System (SCS Analyzer)
Confluence Label	keithley-4200-scs-analyzer
Process Area	CHARACTERIZATION
Model	4200
Vendor	TEKTRONIX, INC.
Team	Nastaran Yousefi Devin Fortier
Location	CME-L2-154

[blocked URL](#)

System Features

Measurement Type	I-V & C-V sweeps Advanced ultrafast pulsed I-V, Waveform capture, Transient I-V,
Temperature Stage	−25 °C to 150 °C
Probe Station	Signatone WL-1160
Max watts	2.1 w
Frequency range	1kHz to 10MHz variable.
Current Range:	±100mA, 7 ranges from 100nA to 100mA full scale.
Voltage Range:	±210V, 4 ranges from 200mV to 210V full scale

Key Documents

SOP	
Hazard Assessment	Keithley 4200 SCS Analyzer -HA

Related Documents

- [Fluxim Paios Spectrometer](#) (Equipment)
 - [equipment](#)
 - [led](#)
 - [oled](#)
 - [characterization](#)
 - [fluxim-paios-spectrometer](#)
 - [spectrometer](#)